•	Sear	ch N	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/626,436	JENSEN ET AL.
Examiner	Art Unit
Jennifer A. Leung	1797

	SEARCHED			
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
updated inventor search.	12/12/2007	JAL
updated search, text only within class/subclass.	12/12/2007	JAL
NPL search, www.sciencedirect.com: nanoparticle, nanocrystal, microreactor, microchannel, microfluidic	12/12/2007	JAL
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